

Costuslactone B¹

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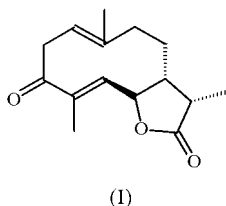
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The crystal structure of 4,10,11 α -trimethyl-3-oxocostuslactone, C₁₅H₂₀O₃, a new compound isolated from the dried root of *Vladimiria souliei* Liarke, has been determined and the compound has been named costuslactone B. The ten-membered ring takes a slightly distorted boat–chair–chair conformation typical of the substituents.

Comment

This work forms part of a series of studies on traditional Chinese medicinal herbs aimed at looking for bioactive drugs. The title compound, (I), was extracted from the dried root of *Vladimiria souliei* Liarke, which is widespread in the west of Sichuan province and the south of neighbouring Gansu province. The herb is used in traditional Chinese medicine for relieving uneasiness and stomach ache, and it also has some antitumour function. Similar structures of sesquiterpene lactones have been reported (Breton *et al.*, 1985; Gomez-Rodriguez *et al.*, 1985).



The configuration shown in the scheme above and in Fig. 1 is the relative configuration. The conformation of the ten-membered ring of (I) is boat–chair–chair and it is slightly distorted owing to the influence of the substituents. The dihedral angles between planes 1 (C3/C2/C4) and 2 (C1/C2/C4/C5), 2 and 3 (C10/C1/C5/C6), 3 and 4 (C9/C10/C6/C7), and 4 and 5 (C8/C7/C9) are 64.2 (3), 46.2 (1), 63.2 (1) and 62.9 (2)°, respectively. The lactone ring has an envelope conformation.

¹ Systematic name: 3,6,10-trimethyl-2,3,3a,4,5,8,9,11a-octahydrocyclodeca[1,2-b]furan-2,9-dione.

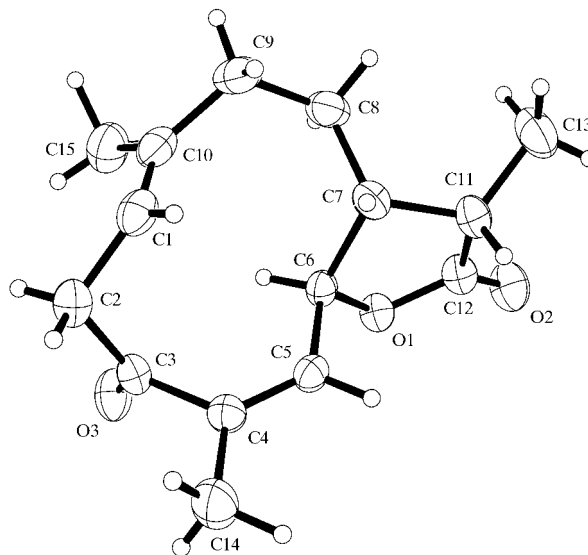


Figure 1

A view of (I) showing the labelling of the non-H atoms. Displacement ellipsoids are shown at the 50% probability level and H atoms are drawn as small circles of arbitrary radii.

Experimental

The air-dried powdered roots of *Vladimiria souliei* Liarke (4.5 kg) were extracted with Et₂O for 7 d. When this Et₂O extract was concentrated, crystals of (I) were precipitated. The experimental sample was recrystallized from ethyl alcohol–acetone mixed solvent.

Crystal data

C₁₅H₂₀O₃
M_r = 248.31
 Orthorhombic, *P*2₁2₁2₁
a = 5.553 (1) Å
b = 12.340 (1) Å
c = 20.875 (2) Å
V = 1430.4 (3) Å³
Z = 4
D_x = 1.153 Mg m⁻³

Mo *K*α radiation
 Cell parameters from 25
 reflections
 θ = 10–20°
 μ = 0.079 mm⁻¹
T = 293 (2) K
 Block, colourless
 0.5 × 0.5 × 0.4 mm

Data collection

Enraf–Nonius CAD-4 diffractometer
 $\omega/2\theta$ scans
 2409 measured reflections
 2409 independent reflections
 2194 reflections with *I* > 2σ(*I*)
 θ_{\max} = 30.63°

h = 0 → 7
k = 0 → 17
l = 0 → 29
 3 standard reflections
 frequency: 60 min
 intensity decay: <0.1%

Refinement

Refinement on *F*²
R [*F*² > 2σ(*F*²)] = 0.031
wR (*F*²) = 0.137
S = 1.239
 2409 reflections
 164 parameters
 H-atom parameters constrained

$w = 1/[\sigma^2(F_o^2) + (0.0644P)^2 + 0.1316P]$
 where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\max} < 0.001$
 $\Delta\rho_{\max} = 0.138 \text{ e \AA}^{-3}$
 $\Delta\rho_{\min} = -0.137 \text{ e \AA}^{-3}$
 Extinction correction: *SHELXL97*
 (Sheldrick, 1997)
 Extinction coefficient: 0.044 (5)

Data collection: *CAD-4 Software* (Enraf–Nonius, 1985); cell refinement: *CAD-4 Software*; data reduction: *MOLLEN* (Fair, 1987); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997);

program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997);
molecular graphics: *XP* in *SHELXTL/PC* (Siemens, 1994).

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Supplementary data for this paper are available from the IUCr electronic archives (Reference: TA1253). Services for accessing these data are described at the back of the journal.

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